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10/658,367 Examiner LOMNITZ, YUVAL

Applicant(s)/Patent under Reexamination

Art Unit

2616

PHUC H. TRAN

SEARCHED				
Class	Subclass	Date	Examiner	
370	203,204 205,206 207,208 209	2/28/2008	РТ	
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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
consulted with Frank Duong; Steven Nguyen	2/15/2008	PT
IEEE search; CiteSeer with Steven Nguyen	2/25/2008	PT
East search see history printout	2/28/2008	PT
Consulted with Khai Tran	1/23/2008	РТ
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